手 続 補 正 書 (Amendment) (法第6条の規定による命令に基づく補正) of drawings

特許庁長官 殿

1. 国際出願の表示 PCT/JP2004/017361

2. 出 願 人

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NATIONAL INSTITUTE OF ADVANCED INDUSTRIAL SCIENCE AND

TECHNOLOGY

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国籍 日本国 Japan

住所 日本国 Japan

3. 補正命令の日付 07.12,2004

4. 補正の対象 図面

5. 補正の内容 別紙のとおり

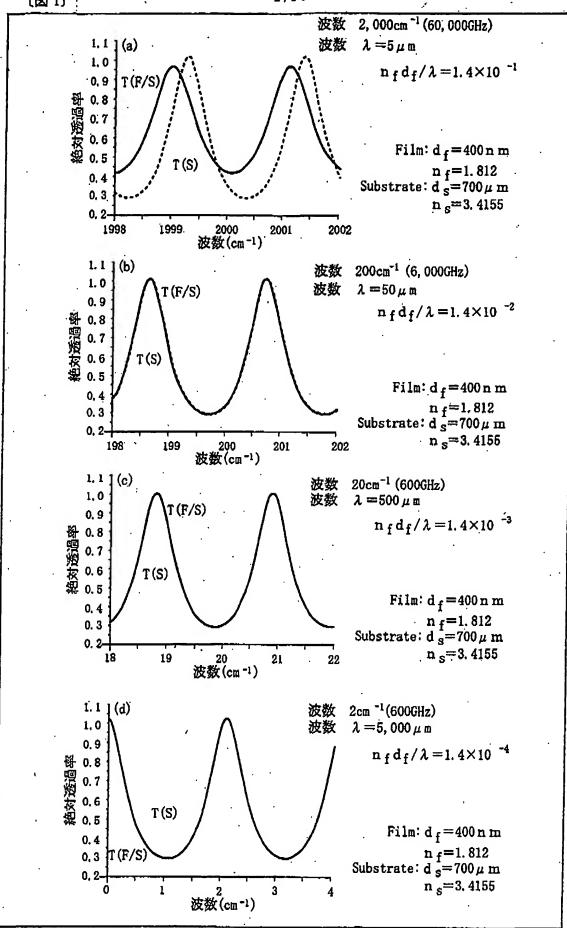
図1、図2、図4~図6、図11を鮮明にする。

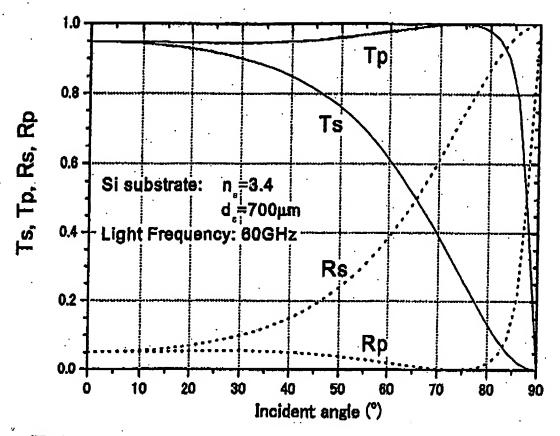
図2~図13、図15の不要な記載を削除する。

図2~図6、図11、図13(a)の文字と線の重なりを解消

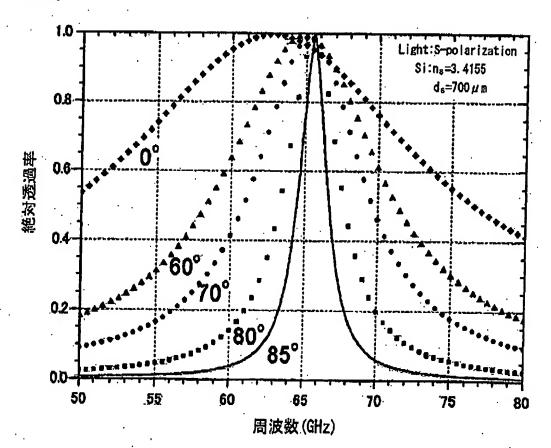
する。

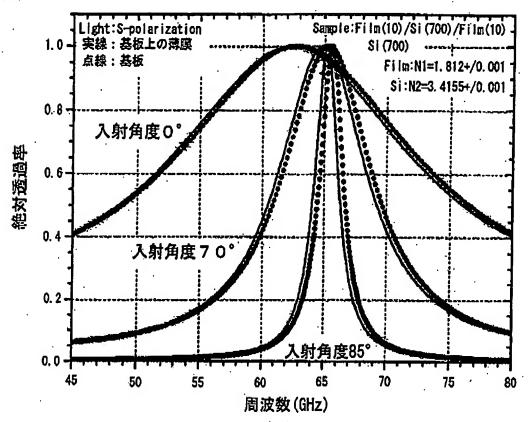
6. 添付書類の目録 図面 1/13、2/13、3/13、4/13、5/13、6/13、7/13、8/13、 9/13、10/13、11/13、13/13頁 (図1):

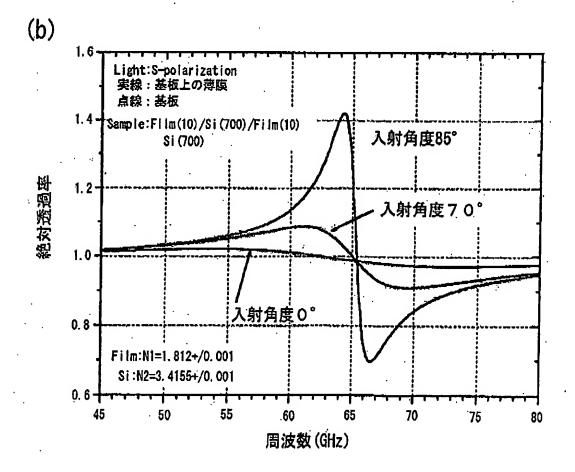


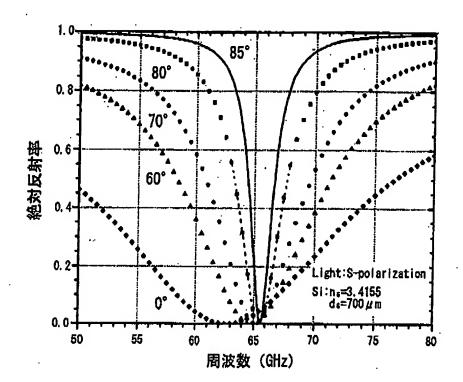


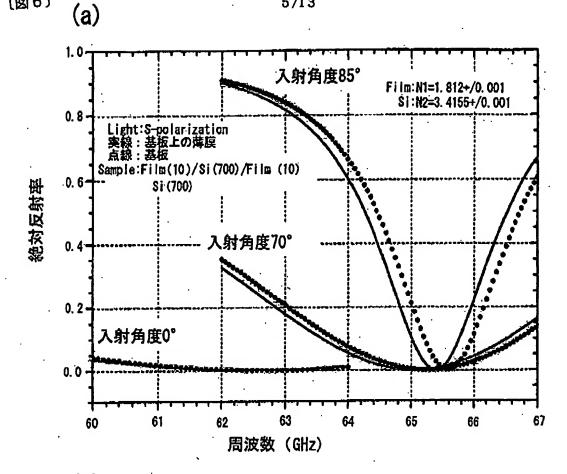


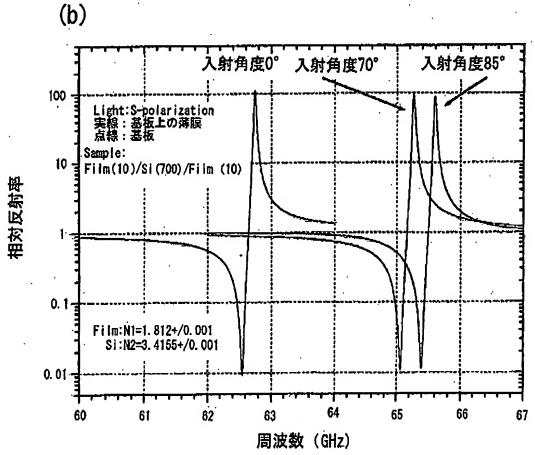


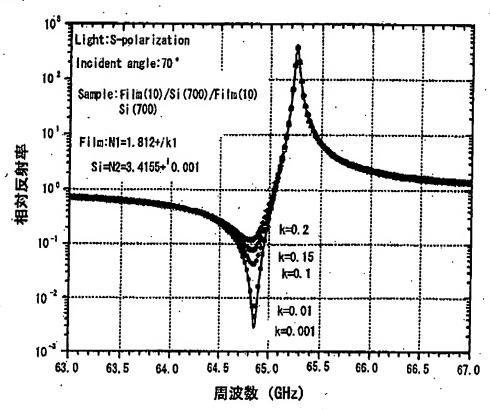




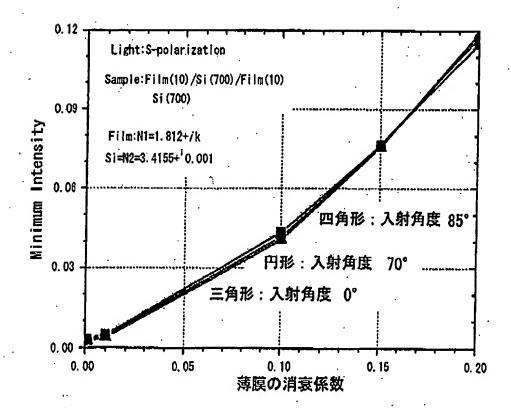


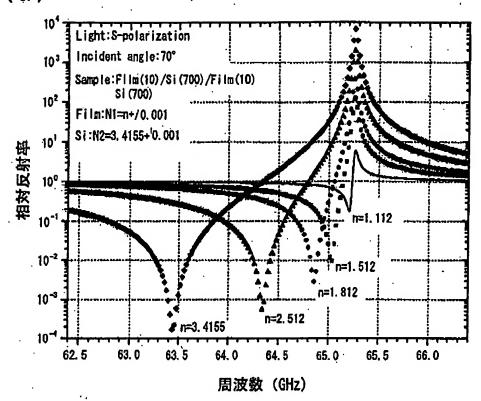




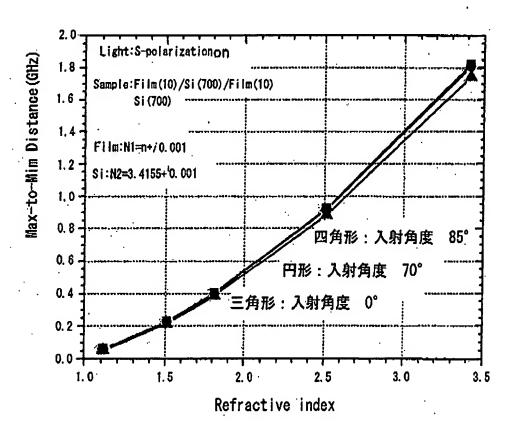


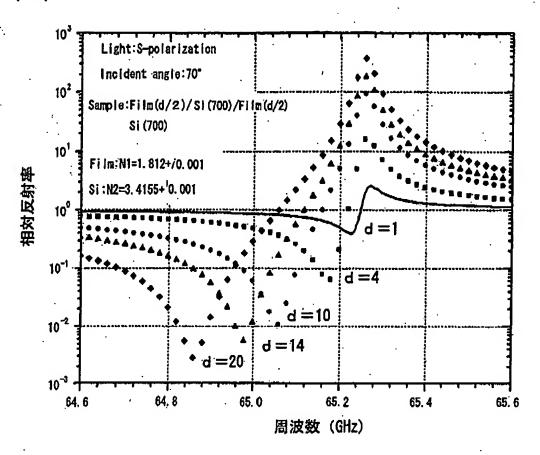
(b)



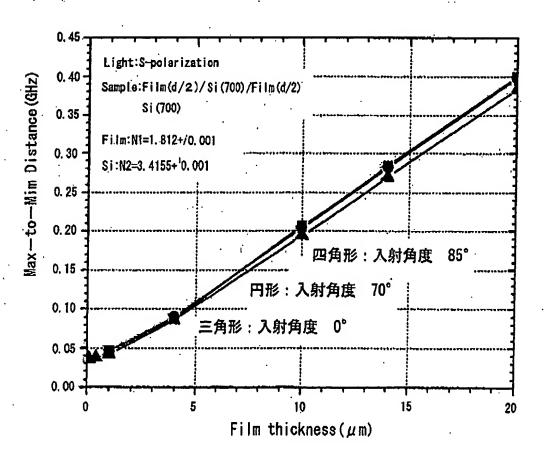


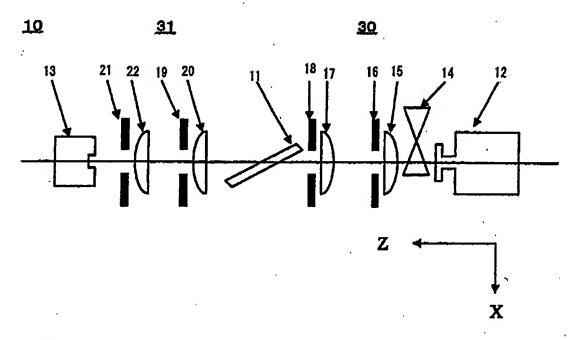
(b)



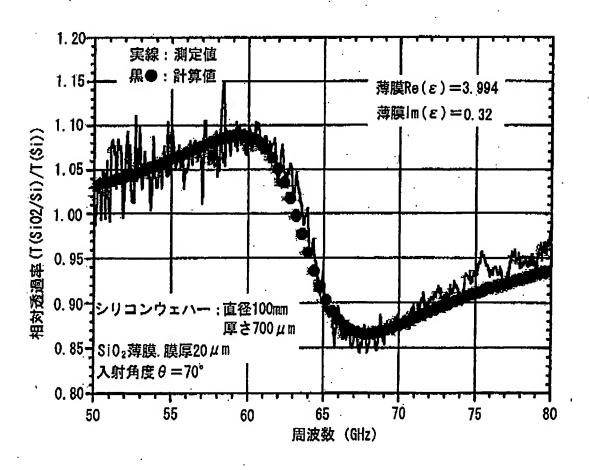


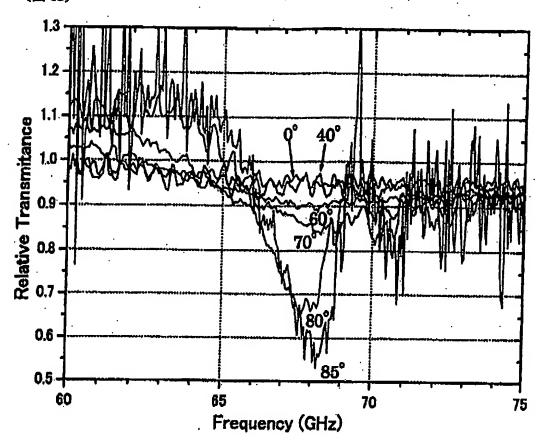


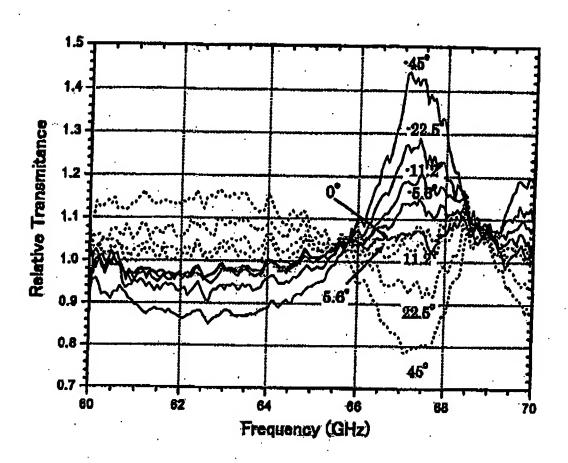


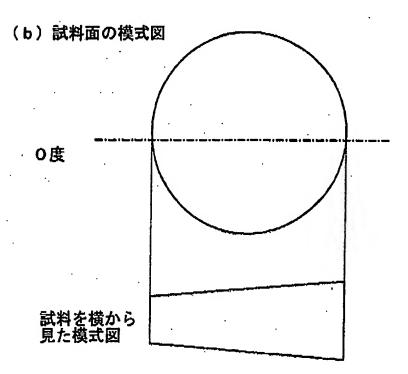


(四 11)





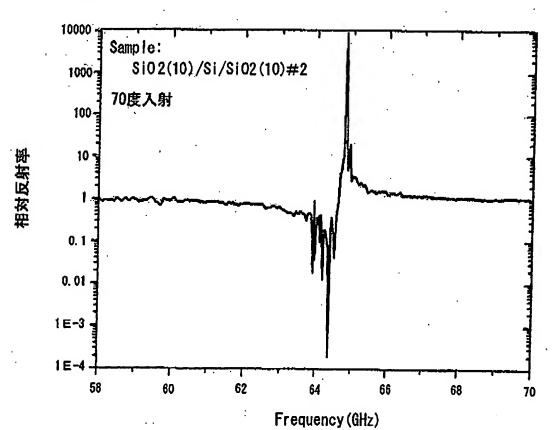




Sample:Si02(10)/Si/Si02(10)#2 点線: Si面 実線: Si02面 70度入射

0. 0 62 63 64 65 66 67 Frequency (GHz)





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